

IN THE
UNITED STATES PATENT AND TRADEMARK OFFICE

Inventor(s): Gary Ray Ashton et al.

Confirmation Number:

Application No.:

Examiner:

Filing Date: Herewith

Group Art Unit: Unkn.

Title: STORAGE DEVICE HAVING A RESISTANCE MEASUREMENT SYSTEM

Commissioner for Patents
PO Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

This Information Disclosure Statement is submitted:

- (X) under 37 CFR 1.97(b), or
(Within three months of filing national application; or date of entry of national application; or before mailing date of first office action on the merits; whichever occurs last)
- () under 37 CFR 1.97(c) together with either a:
() Statement under 37 CFR 1.97(e), or
() a \$180.00 fee under 37 CFR 1.17(p), or
(After the 37 CFR 1.97 (b) time period, but before final action or notice of allowance, whichever occurs first)
- () under 37 CFR 1.97 (d) together with a:
() Statement under 37 CFR 1.97(e)(1) or (2), and
() a \$180.00 fee set forth in 37 CFR 1.17(p).
(Filed after final action, a notice of allowance, on or before payment of the issue fee)

Please charge to Deposit Account **08-2025** the sum of \$0.00. At any time during the pendency of this application, please charge any fees required or credit any overpayment to Deposit Account **08-2025** pursuant to 37 CFR 1.25.

(X) Applicant(s) submit herewith Form PTO 1449 - Information Disclosure Statement together with any required copies of patents, publications or other information of which applicant(s) are aware, which applicant(s) believe(s) may be material to the examination of this application and for which there may be a duty to disclose in accordance with 37 CFR 1.56.

() A concise explanation of the relevance of foreign language patents, foreign language publications and other foreign language information listed on PTO Form 1449, as presently understood by the individual(s) designated in 37 CFR 1.56 (c) most knowledgeable about the content is given on the attached sheet, or where a foreign language patent is cited in a search report or other action by a foreign patent office in a counterpart foreign application, an English language version of the search report or action which indicates the degree of relevance found by the foreign office is listed on form PTO 1449 and is enclosed herewith.

It is requested that the information disclosed herein be made of record in this application.

* Express Mail* label no. EV409552245US

Date of Deposit Jan. 13, 2004

I hereby certify that this is being deposited with the United States Postal Service "Express Mail Post Office to Addressee" service under 37 CFR 1.10 on the date indicated above and is addressed to: Commissioner for Patents, Alexandria, VA 22313-1450.

By

Typed Name: V. melle Beal

Respectfully submitted,

Gary Ray Ashton et al.

By Steven E. Dicke

Steven E. Dicke

Attorney/Agent for Applicant(s)
Reg. No. 38,431

Date: Jan. 13, 2004

PATENT APPLICATION

Sheet 1 of 1

FORM PTO-1449 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTY. DOCKET NO. 10011206-1	APPLICATION NO.	CONFIRMATION NO.
APPLICANT Gary Ray Ashton t al.			
FILING DATE Her with		GROUP Unkn.	

REFERENCE DESIGNATION U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	PUBLICATION DATE	NAME	Pages, Columns, Lines Where Relevant Passages or Figures Appear
	1A	4,583,128	04/1986	Anderson, Jr. et al.	
	1B	5,124,183	06/1992	Nakano et al.	
	1C	5,557,596	09/1996	Gibson et al.	
	1D	5,940,106	08/1999	Walker	
	1E	6,087,674	07/2000	Ovshinsky et al.	
	1F				
	1G				
	1H				
	1I				
	1J				
	1K				

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	PUBLICATION DATE	NAME OF PATENTEE OR APPLICANT	Pages/Columns/Lines Where Relevant Passages/Figures Appear	Check if Translation attached
	1L					
	1M					
	1N					
	1O					
	1P					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

	1Q	D.B. Holt, "The Remote Electron Beam-Induced Current Analysis of Grain Boundaries in Semiconducting and Semi-Insulating Materials," Accepted October 1, 1999, pgs. 1-24.
	1R	
	1S	

EXAMINER	DATE CONSIDERED
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